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Artificial Intelligence Approach for IoT and Edge Computing Applications

Guest Editor:

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Message from the Guest Editor

This Special Issue aims to promote high-quality research into all aspects of designing AI approaches for IoT and EC applications.

Topics of interest include, but are not limited to:

- Computational offloading for IoT and EC applications;
- DL solutions for resource allocation and management in IoT and EC applications;
- Al-enabled communication and routing protocols for IoT and EC applications;
- Privacy and reliability solutions for IoT and EC applications;
- Al-based security solutions for edge and IoT nodes;
- Blockchain solutions for IoT and EC applications;
- DL for privacy preservation in IoT and EC applications;
- Federated learning for IoT and edge computing;
- Edge learning for IoT and Industrial IoT applications;
- Al-based real-time protocols for IoT and EC applications.

We look forward to receiving your contributions.











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Editor-in-Chief

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Message from the Editor-in-Chief

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